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Fairchild Semiconductor FDZ202P

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## FDZ202P

### P-Channel 2.5V Specified PowerTrench<sup>®</sup> BGA MOSFET

#### **General Description**

Combining Fairchild's advanced 2.5V specified PowerTrench process with state of the art BGA packaging, the FDZ202P minimizes both PCB space and  $R_{DS(ON)}$ . This BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultralow profile packaging, low gate charge, and low  $R_{DS(ON)}$ .

#### Applications

- Battery management
- Load switch
- Battery protection

#### Ultra-thin package: less than 0.80 mm height when mounted to PCB

**Features** 

area of SSOT-6

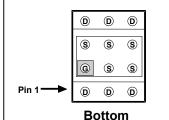
• Outstanding thermal transfer characteristics: 4 times better than SSOT-6

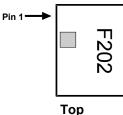
•  $-5.5 \text{ A}, -20 \text{ V}. \text{ R}_{\text{DS(ON)}} = 45 \text{ m}\Omega \text{ @ V}_{\text{GS}} = -4.5 \text{ V}$ 

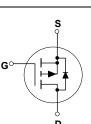
• Occupies only 5 mm<sup>2</sup> of PCB area: only 55% of the

 $R_{DS(ON)}$  = 75 m $\Omega$  @ V<sub>GS</sub> = -2.5 V

- Ultra-low  $Q_g x R_{DS(ON)}$  figure-of-merit
- High power and current handling capability







FDZ202P

January 2004

#### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		±12	V
ID	Drain Current – Continuous	(Note 1a)	-5.5	Α
	– Pulsed		-20	
PD	Power Dissipation (Steady State)	(Note 1a)	2	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temper	rature Range	–55 to +150	°C

#### **Thermal Characteristics**

R <sub>0JA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	64	°C/W
R <sub>0JB</sub>	Thermal Resistance, Junction-to-Ball	(Note 1)	8	°C/W
R <sub>0JC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	0.7	°C/W

#### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
202P	FDZ202P	7"	8mm	3000 units
2021	I DEEVEI	,		0000

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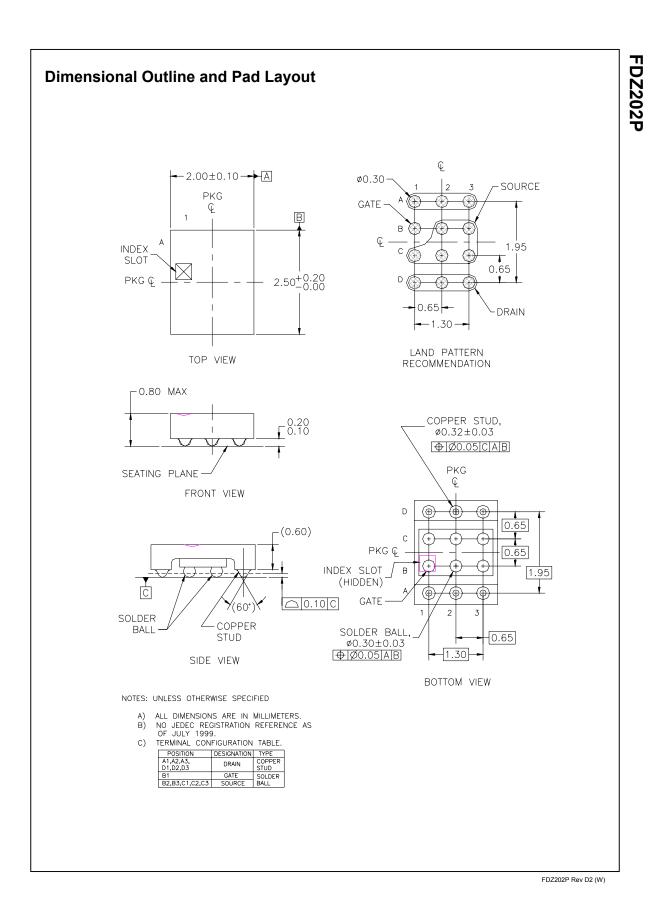


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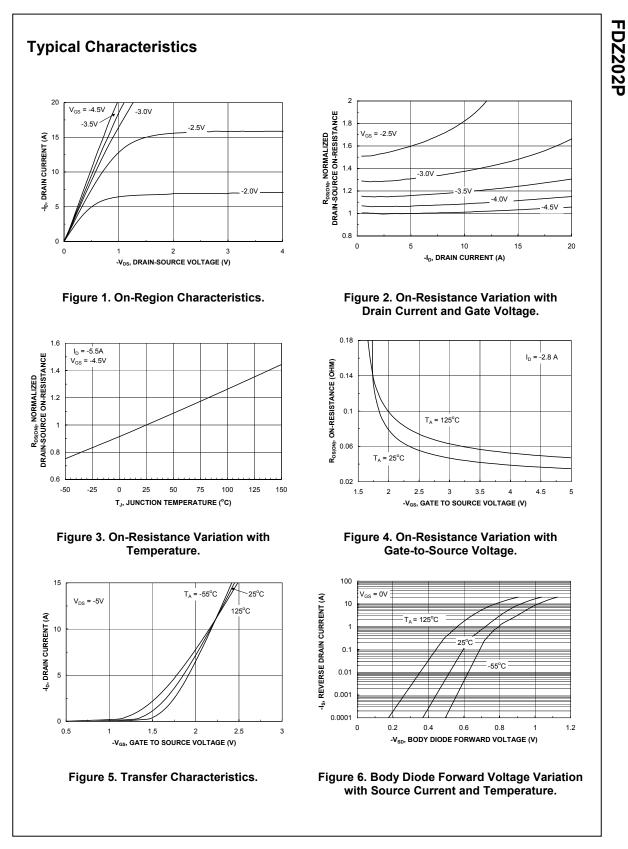
# FDZ202P

FDZ202P Rev D2 (W)



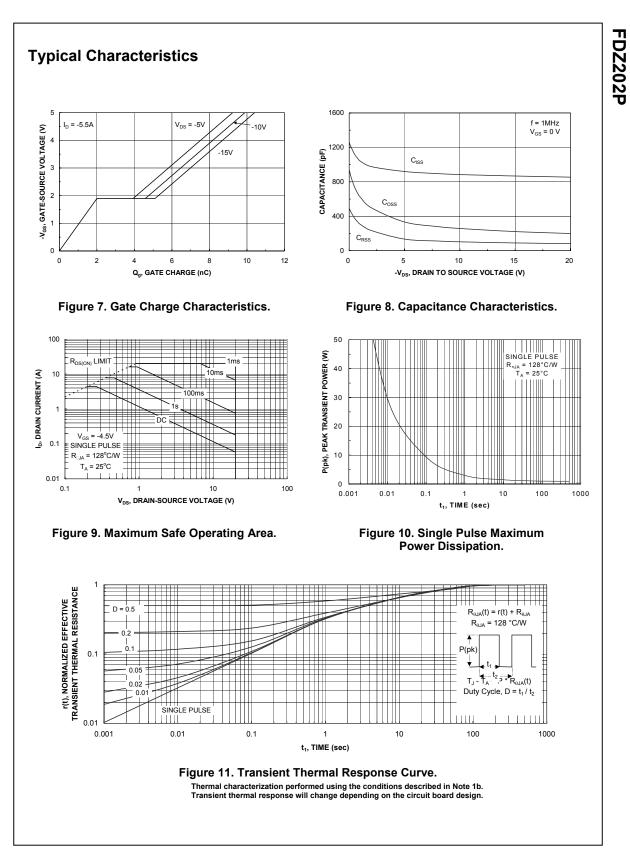






FDZ202P Rev D2 (W)





FDZ202P Rev D2 (W)



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